

<b>Notice of References Cited</b>	Application/Control No. 10/604,964	Applicant(s)/Patent Under Reexamination HOSSAIN, RAZAK	
	Examiner Naum B. Levin	Art Unit 2825	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,946,903 B2	09-2005	Marshall et al.	327/566
*	C	US-7,058,834 B2	06-2006	Woods et al.	713/324
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Abdollahi et al. "Leakage current reduction in sequential circuits by modifying the scan chains", Fourth international symposium on 24-28 March 2003".
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.